

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Shimpei MIURA et al.

Application No.: 10/714,645

Filed: November 18, 2003

Docket No.: 116909

For: FLUID LEAKAGE DETECTION APPARATUS AND FLUID LEAKAGE DETECTION METHOD

INFORMATION DISCLOSURE STATEMENT

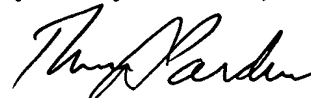
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- ☒ 2. English-language Abstracts of the non-English language references are attached hereto. (Refs. 1-3)
- ☒ 3. Computer-generated English translations of the following Japanese Patent Publication have been obtained from the website of the Japanese Patent Office (<http://www.jpo.go.jp>), and are attached, but have not been reviewed for accuracy. See References 1-2.

Respectfully submitted,



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Date: February 18, 2004

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Form PTO-1449  
(REV. 8-83)US Dept. of Commerce  
PATENT & TRADEMARK OFFICEATTY DOCKET NO.  
116909APPLICATION NO.  
10/714,645

## INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANTS  
Shimpei MIURA et al.FILING DATE  
November 18, 2003

## U.S. PATENT DOCUMENTS

| EXAMINER<br>INITIAL |  | DOCUMENT NUMBER | DATE | NAME | CLASS | SUB<br>CLASS |
|---------------------|--|-----------------|------|------|-------|--------------|
|                     |  |                 |      |      |       |              |
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|                     |  |                 |      |      |       |              |

## FOREIGN PATENT DOCUMENTS

|  |   | DOCUMENT NUMBER                  | DATE       | COUNTRY | CLASS | SUB<br>CLASS |
|--|---|----------------------------------|------------|---------|-------|--------------|
|  | 1 | JP A 2002-227727 w/ abst & trans | 08/14/2002 | Japan   |       |              |
|  | 2 | JP A 2001-159375 w/ abst & trans | 06/12/2001 | Japan   |       |              |
|  | 3 | JP A 2-176440 w/ abst            | 07/09/1990 | Japan   |       |              |
|  |   |                                  |            |         |       |              |
|  |   |                                  |            |         |       |              |

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

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EXAMINER

DATE CONSIDERED

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: February 18, 2004